

**Search Notes**

Application/Control No.

10/665,469

Examiner

Phillip Nguyen

Applicant(s)/Patent under  
Reexamination

ONISHI, TOSHIKAZU

Art Unit

2828

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search (see the printout)	4/21/2006	PN